Search Notes



Appl	ica	tion	Control	No.

10/722,991 Examiner

Toan M. Le

Applicant(s)/Patent under Reexamination

HOYTE, SCOTT MORDIN

Art Unit

2863

	SEAR	CHED	
Class	Subclass	Date	Examiner
702	65	3/30/2005	TL
324	207.16	3/30/2005	TL
324	207.11	3/30/2005	TL
324	207.26	3/30/2005	TL
324	699	3/30/2005	TL
324	716	3/31/2005	TL
			_

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		<u> </u>			

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Gap Determination, Impedance, Material Property	3/30/2005	TL
Gap, Eddy Curent Proximity Sensor Probe	3/31/2005	TL
Proximity Probe	3/31/2005	TL
East, Web, and NPL search		
•		